WHAT IS CLAIMED IS:

1. A method for estimating repair accuracy of a mask shop comprising the steps of:

providing a mask having a light-shielding layer with a pattern of a plurality of lines, each of which has a defect;

using the mask shop to repair the defects, whereby contaminated areas are formed in the vicinity of areas where the defects are repaired;

measuring first light intensities of the contaminated areas, and second and third light intensities of two sides of the contaminated areas; and

calculating ratios of means of the second and third light intensities to the first light intensities for estimating the repair accuracy.

2. The method as claimed in claim 1 further comprising the step of:

calculating a mean and 3δ value of the ratios.

3. The method as claimed in claim 1 wherein the lines comprise a plurality of vertical and horizontal lines.

4. The method as claimed in claim 3 wherein widths of the lines range from $0.5\,\mu$m to $2\,\mu$m.

5. The method as claimed in claim 1 wherein widths of the defects along the lines range from $0.3\,\mu$m to $1.5\,\mu$m.

1   6. The method as claimed in claim 1 wherein the defects

2   are indentations on the lines.

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1   7. The method as claimed in claim 1 wherein the light-

2   shielding layer is a chrome layer.